Silicon MOSFETs (Small Signal)

 $0.15\substack{+0.10 \\ -0.05}$

Unit: mm

0.2±0.

MTM23223

Silicon N-channel MOSFET

For switching circuits

Features

- Low voltage drive (2.5 V, 4 V)
- · Realization of low on-resistance, using extremely fine process

Absolute Maximum Ratings $T_a = 25^{\circ}C$

Parameter	Symbol	Rating	Unit	
Drain-source surrender voltage	V _{DSS}	20	V	
Gate-source surrender voltage	V _{GSS}	±10	V	
Drain current	ID	4.5	А	
Peak drain current *1	I _{DP}	18	А	
Power dissipation *2	P _D	500	mW	
Channel temperature	T _{ch}	150	°C	
Storage temperature	T _{stg}	-55 to +150	°C	

Note) *1: Pulse width $\leq 10 \ \mu$ s, Duty Cycle $\leq 1\%$

*2: Measuring on ceramic substrate at 40 mm \times 38 mm \times 0.1 mm Absolute maximum rating without heat sink for P_p is 150 mW



(0.425)

1.25±0.10 2.1±0.1

0.9±0.0

Marking Symbol: BK

0.3+0.1

(0.65) (0.65)

1.3±0.1 2.0±0.2

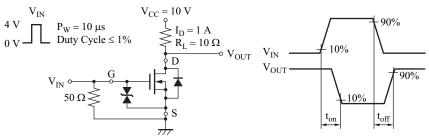
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Electrical Characteristics $T_a = 25^{\circ}C + 3^{\circ}C$									
Parameter	Symbol	Conditions	Mir	Тур	Max	Unit			
Drain-source surrender voltage	V _{DSS}	$I_D = 1 \text{ mA}, V_{GS} = 0$	S 20			V			
Drain-source cutoff current	I _{DSS}	$V_{\rm DS} = 20 \text{V}, V_{\rm GS} = 0$			1.0	μΑ			
Gate-source cutoff current	I _{GSS}	$V_{GS} = \pm 8 V, V_{DS} = 0$			±10	μΑ			
Gate threshold voltage	V _{TH}	$I_D = 1.0 \text{ mA}, V_{DS} = 10.0 \text{ V}$	0.4	0.85	1.3	V			
Drain-source ON resistance *1	D	$I_{\rm D} = 1.0 \rm A, V_{\rm GS} = 4.0 \rm V$		20	28	mΩ			
	R _{DS(on)}	$I_D = 0.6 A_2 V_{GS} = 2.5 V$		26	40				
Forward transfer admittance *1	Y _{fs}	$I_{D} = 0$ A, $V_{DS} = 10$ V, f = 1 kHz	3.5			S			
Short-circuit forward transfer capacitance (Common source)	C _{iss}	sit nit		1 200		pF			
Short-circuit output capacitance (Common source)	Coss	$V_{DS} = 10 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$		85		pF			
Reverse transfer capacitance (Common source)	C _{rss}			80		pF			
Turn-on time *2	t _{on}	$V_{DD} = 10 \text{ V}, V_{GS} = 0 \text{ V} \text{ to } 4 \text{ V}, I_D = 1 \text{ A}$		16		ns			
Turn-off time *2	t _{off}	$V_{DD} = 10 \text{ V}, V_{GS} = 4 \text{ V to } 0 \text{ V}, I_D = 1 \text{ A}$		220		ns			

Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

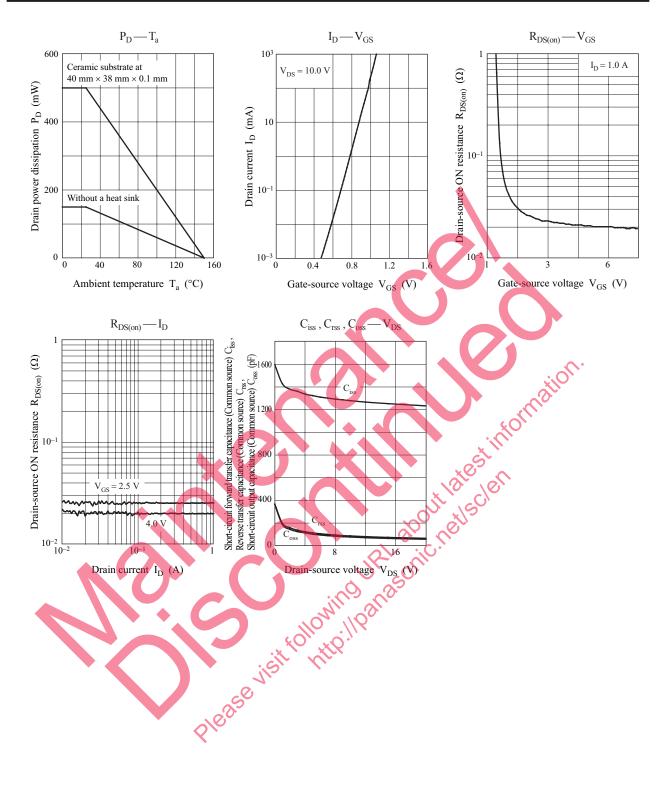
2. *1: Pulse measurement: Pulse width < 300 μ s, Duty Cycle < 2%

*2: t_{on} , t_{off} measurement circuit



MTM23223

Panasonic



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